Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10707003	BENTWICH, ITZḤAK
Examiner	Art Unit
Shin, Dana	1635

SEARCHED					
Class	Subclass	Date	Examiner		
536	23.1, 24.5	6-27-07, 9-5-07	DS		
435	6	6-27-07, 9-5-07	DS		

SEARCH NOTES				
Search Notes	Date 6-26-07	Examiner DS		
STIC - SEQ ID NOs: 3588 (Score over length) search results available on SCORE				
EAST - updated	6-27-07, 9-5-07	DS		
PALM - inventor name search	6-27-07	DS		
STIC - SEQ ID NO:3588 for 83%, search results available on SCORE	10-26-07	DS		

INTERFERENCE SEARCH				
Class	Subclass	Date	Evamina	
Class	Subciass	Date	Examine	

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